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1.SCOPE:

This specification covers the requirements for product performance of 5.08mm pitch wire to wire to board connector series.

2.PART NAME & PART NUMBER:

Part Name		Part Number	
Housing		C5081HF C5081HM	
Terminal	F-T	C5081F-T	
	M-T	C5081M-T	
Wafer		C5081WV C5081WR	

3.CONSTRUCTION, DIMENSIONS, MATERIAL & SURFACE FINISH:

Construction and dimensions shall be in accordance with the referenced drawings.

Material and surface finish shall be as specified below.

Part Name	Material			Surface finish	
Housing	Nylon 66			UL94V-0/UL94V-2	
Terminal			/Phosphor Bronze		
Terminai	М-Т	Brass/Phosphor Bronze		Tin over Nickel/Gold over	
Wafar	Вс	ody	Nylon 66	UL94V-0/UL94V-2	
Wafer	P	in	Brass	Tin over Nickel/Gold over	

4. CHARACTERISTICS:

Current rating: 7A AC,DC Voltage rating: 250V AC,DC

Temperature range: $-40^{\circ}\text{C} \sim 105^{\circ}\text{C}$

5. CONDITIONS:

The conditions shall be in accordance with the referenced drawing of next page.

Number	Item	Requirement
	Bend up	4°max.
	Bend down	4°max.
(1)	Twisting	3°max.
	Rolling	8°max.
2	Bell mouth (flare)	0.2-0.5 mm
3	Cut-off tab length	0.2 mm max.
4	Extruded wire length	0-1.5 mm
(5)	Seam	Seam shall not be opened and no wire allowed out
6	Wire strip length	1.2-1.7 mm ref.
7	Lance height	0.3 mm ref.



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6. MECHANICAL TEST

6.1 Crimp width crimp height & crimp strength

After crimping, the crimped areas [⑤、⑥] should be as follows.

Wina Cina	T1 D4	Conductor(mm)		Insulation(mm)		Crimp
Wire Size (AWG)	Terminal Part Number	Crimp	Crimp	Crimp	Crimp	Strength
(11,1,0)		Width	Height	Width	Height	(Kg)
#18	C5081F-T C5081M-T	1F-T 1.78±0.15	1.22		2.10(max)	9.00(min)
#20			1.09	2.54(may)	2.00(max)	8.00(min)
#22		1./8±0.13	1.02	2.54(max)	1.90(max)	7.00(min)
#24			0.97		1.80(max)	6.00(min)

Note: no distorted after terminal crimped.

6.2 INSERTION FORCE (I.F.) & WITHDRAWAL FORCE (W.F.)

(1) Requirement: Insertion & withdrawal at least 50 times (unit : kgf)

Number of	At initial		At 50th
Circuits	I.F. (max)	W.F. (min)	W.F. (min)
Single	2.00	0.50	0.20
2	4.00	1.00	0.40
3	6.00	1.50	0.60
4	8 00	2 00	0.80

N=10

(2) Test method: Housing with crimped terminal and wafer shall be mated and unmated on the same axis. Initial insertion and withdrawal forces and withdrawal forces at 50th shall be measured for single circuit and multi-circuits. For the measurement of single circuit, housing lock shall be removed.

Insertion and withdrawal speed: 25.4± 5 mm/minute.



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(3) Test results: (unit: kgf)

N=10

Num	ber of	At initial		At 50th
Circ	cuits	I.F.	W.F.	W.F.
	max	3.16	1.06	0.95
Single	min	2.64	0.64	0.41
	Ave.	2.98	0.87	0.82
	max	4.29	1.66	1.53
2	min	3.50	1.24	1.16
	Ave.	4.02	1.41	1.28
	max	5.34	2.70	2.61
3	min	4.03	1.75	1.54
	Ave.	4.88	2.28	2.13
	max	6.39	3.73	3.61
4	min	4.35	2.16	1.83
	Ave.	5.67	3.09	2.98



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6.3 CRIMP TENSILE STRENGTH

(1) Requirement & Test results: (unit: kgf)

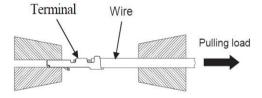
N = 10

Wire Size (AWG)	Requirements (min)	Max	Min	Ave.
#18	9.00	12.50	11.30	11.50
#20	5.90	8.25	8.11	8.15
#22	3.90	5.84	5.20	5.35
#24	2.90	4.15	4.05	4.10

(2) Test method: Crimped terminal shall be mounted in a housing and pulled in an alignment.

The load to pull the terminal out of the housing shall be measured.

Insertion and withdrawal speed: 25.4 mm/minute.



6.4 CONTACT RETENTION FORCE (HF)

- (1) Requirement: 4.5 kgf (min.)
- (2) Test method: Crimped terminal shall be mounted in a housing(HF) and pulled in an alignment. The load to pull the terminal out of the housing shall be measured.

Insertion and withdrawal speed: 25.4± 5 mm/minute.

(3) Test results:

N=10

Max.	Min.	Ave.
9.15	6.20	7.52

6.5 CONTACT RETENTION FORCE (HM)

- (1) Requirement: 4.5 kgf (min.)
- (2) Test method: Crimped terminal shall be mounted in a housing(HM) and pulled in an alignment. The load to pull the terminal out of the housing shall be measured.

Insertion and withdrawal speed: 25.4± 5 mm/minute.

(3) Test results:

N = 10

Max.	Min.	Ave.
9.95	7.80	8.48



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6.6 POST RETENTION FORCE

(1) Requirement: 1.5 kgf (min.)

(2) Test method: The end of a post shall be pushed in a perpendicular to wafer. The load to make the post start moving shall be measured.

Insertion and withdrawal speed: 25.4 mm/minute.

(3) Test results:

N = 10

Max.	Min.	Ave.
5.32	4.10	4.80

7. ELECTRICAL TEST:

7.1 Contact resistance

(1) Requirement: Initial: $10 \text{ m}\Omega \text{ (max.)}$

After environmental test : 20 m Ω (max.)

(2) Condition: Test current: 10 mA (DC)

Open voltage: 20mV (max.)

(3) Test result: See items $8.1 \sim 8.5$

7.2 Insulation resistance

(1) Requirement: Initial: $1000 \text{ M}\Omega \text{ (min.)}$

After humidity test: $500 \text{ M}\Omega \text{ (min.)}$

After thermal shock test : $500 \text{ M}\Omega \text{ (min.)}$

(2) Test method: DC 500V shall be applied between outer surface of housing and terminal and between adjacent terminals to measure insulation resistance.

(MIL-STD-202, test method 302, condition B)

- (3) Test result: See items 8.2 & 8.5
- 7.3 Dielectric withstanding voltage
 - (1) Requirement: There shall be no breakdown nor flashover.
 - (2) Test method: Initially AC 1500V (rms) and after humidity and thermal shock tests AC 300V (rms) shall be applied between outer surface of housing and terminal and between adjacent terminals for one minutes. (MIL-STD-202, test method 301)

Test current: 1mA

- (3) Test result: See items 8.2 & 8.5
- 7.4 Temperature Rise
 - (1) Requirement: Temperature rise: +30°C MAXIMUM.
 - (2) Test method: Measure the temperature rise at the rated current.
 - (3) Test result:

Max.	Min.	Ave.
28	24	26



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8. ENVIRONMENT TEST:

- 8.1 Repeated Insertion/Withdrawal
 - (1) Requirement: Contact resistance shall be 20 milliohms (max.) after the test. Insulation
 - (2) Test method: Mated connector shall be mated up to 30 cycles repeatedly by the rate of 10 cycles per minute. After the test, contact resistance shall be measured.

(3) Test result: N=10

Test item	Initial (mΩ)			A	fter test (mΩ	2)
Contact	Max.	Min.	Ave.	Max.	Min.	Ave.
resistance	7.75	5.12	5.85	8.43	8.16	8.34

8.2 Humidity

- (1) Requirement: Contact resistance shall be 20 milliohms (max.) after the test. Insulation resistance shall be 300 megohms (min.) after the test. There shall be no breakdown nor flashover on dielectric withstanding voltage test.
 - (2) Test method: Mated connector shall be placed in a humidity chamber of the following conditions. After the test, contact resistance, insulation resistance and dielectric withstanding voltage shall be measured. (MIL-STD-202, test method 103, condition A)

Temperature : 60 ± 2 °C

Humidity: 90% ~ 95% (RH)

Period: 96 hours continuously

(3) Test results:

Test item	Initial (mΩ)			After test (m Ω)			
Contact	Max.	Min.	Ave.	Max.	Min.	Ave.	
resistance	7.75	5.12	5.85	8.36	8.13	8.22	N=10

 Test item
 Housing-Terminal (MΩ)
 Terminal-Terminal (MΩ)

 Insulation resistance
 Initial
 After test
 Initial
 After test

 1000min
 500min
 1000min
 500min
 N=10

Test item	Housing	-Terminal	Terminal-Terminal		
DWW	Initial	After test	Initial	After test	
D.W.V.	Good	Good	Good	Good	N=10

(D.W.V.: Dielectric withstanding voltage)



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8.3 Salt spray

(1) Requirement: Contact resistance shall be 20 milliohms (max.) after the test.

(2) Test method: Mated connector shall be subjected to salt spray test of the following conditions. After the test, specimen shall be washed with running water and dried naturally before the measurement of contact resistance.

Temperature : 35 ± 2 °C

Humidity: 90% ~ 95% (RH)

Period: 48 hours

(3) Test result:

Test item	Initial (mΩ)			A	fter test (mΩ	2)	
Contact	Max.	Min.	Ave.	Max.	Min.	Ave.	
resistance	7.75	5.12	5.85	8.53	8.16	8.21	N=1

8.4 Heat Resistance & Cold Resistance

(1) Requirement: Contact resistance shall be 20 milliohms (max.) after the test.

(2) Test method: Mated connector shall be placed in a heat oven & cold oven of the following conditions. After the test, contact resistance shall be measured.

Temperature : $+105 \pm 2$ °C

Period: 96 hours

Temperature : -40 ± 2 °C

Period: 96 hours

(3) Test result:

Test item	Initial (mΩ)			After test $(m\Omega)$			
Contact	Max.	Min.	Ave.	Max.	Min.	Ave.	
resistance	7.75	5.12	5.85	8.41	8.11	8.31	N=10



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8.5 Thermal shock

- (1) Requirement: Contact resistance shall be 20 milliohms (max.) after the test. Insulation resistance shall be 500 megohms (min.) after the test. There shall be no breakdown nor flashover on dielectric withstanding voltage test.
- (2) Test method: Mated connector shall be subjected to thermal shock test of the following conditions. After the test, contact resistance, insulation resistance and dielectric withstanding voltage shall be measured.

1 cycle consists of:

-55±3 °C for 30 minutes

+105±2 °C for 30 minutes

Times of cycles: 25 cycles

(3) Test results:

Test item	Initial $(m\Omega)$			After test (m Ω)			
Contact	Max.	Min.	Ave.	Max.	Min.	Ave.	
resistance	7.75	5.12	5.85	8.44	8.15	8.26	N=10

 Test item
 Housing-Terminal (MΩ)
 Terminal-Terminal (MΩ)

 Insulation resistance
 Initial
 After test

 1000min
 500min
 1000min
 500min

Test item	Housing	-Terminal	Terminal-Terminal		
DWW	Initial	After test	Initial	After test	
D.W.V.	Good	Good	Good	Good	N=10

(D.W.V.: Dielectric withstanding voltage)

8.6 Vibration

- (1) Requirements: Contact resistance shall be 20 milliohms (max.) after the test. There shall be no current discontinuity longer than 1 microsecond during the test.
- (2) Test method: Mated connector shall be mounted on a PCB and subjected to a vibration test of the following conditions. During the test, current continuity shall be checked. After the test, contact resistance shall be measured. (MIL-STD-202, test method 201)



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Frequency: 10~55~10 Hz/min.

Amplitude: 1.52 mm

Direction: 1. Axis of X, 2hours

2. Axis of Y, 2hours

3. Axis of Z, 2hours

(3) Test results:

Test item	Initial (mΩ)			After test (m Ω)			
Contact	Max.	Min.	Ave.	Max.	Min.	Ave.	
resistance	7.75	5.12	5.85	8.41	8.11	8.31	N=10

Current discontinuity: There shall be no current discontinuity longer than

1 microsecond during the test.

8.7 Solderability

(1) Requirements: 95% of immersed area must show no voids.pin holes.

(2) Test method: Fluxed soldering section of shrouded header shall be dipped in solder of the following conditions.

Solder temperature : 245 ±3 °C

Immersion period: 3±0.5 seconds

(3) Test result: Good.

8.8 Resistance to soldering heat

(1) Requirements: There shall be no deformation nor damage which may affect the performance.

(2) Test method: Specimen shall be mounted on a PCB (inserted only) and subjected to resistance to soldering heat test of the following conditions.

Solder temperature : 260 ± 5 °C

Immersion period:5±1 seconds

(3) Test result: Good.